

09/887, 475

Type	Hits	Search Text	DBs	Time Stamp	Com ments	Error Defi nition	Error s	Ref #
51	BRS 47	((line\$1 near\$3 (select\$4 pick\$3 choos\$3 chosen)) with ((number\$1 count\$1 frequenc\$3 occurrence\$1) near\$3 (edge\$1 edgepoint\$1 (edge adj1 point\$1)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/06/03 11:25				S51
52	BRS 61	((line\$1 near\$3 (cluster\$3 group\$3 select\$4 pick\$3 choos\$3 chosen)) with ((number\$1 count\$1 frequenc\$3 occurrence\$1) near\$3 (edge\$1 edgepoint\$1 (edge adj1 point\$1)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/06/03 11:26				S52
53	BRS 9	((line\$1 near\$3 (cluster\$3 group\$3 inclu\$5 add\$4)) with ((number\$1 count\$1 frequenc\$3 occurrence\$1) near\$3 (edge adj1 (point\$1 pixel\$1)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/06/03 11:27				S53
54	BRS 580	358/462.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/06/03 13:44				S54
55	BRS 4493	382/101,102,173,175,176,195,198,202,224,225,264,270,281,289.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 15:09				S55
56	BRS 14	((line\$1 near\$3 (ft\$4 interpolat\$3))) and (character\$1 recognition OCR) and @ad<="20010625" and (text near\$3 (block\$1 segment\$1 region\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/05/31 12:37				S57
57	BRS 79	((line\$1 near\$3 (ft\$4 interpolat\$3))) and (character\$1 recognition OCR) and @ad<="20010625"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/05/31 12:37				S56
58	BRS 107	((smeat\$3 project\$3) same ((line\$1 edge\$1) near\$3 (detect\$3 locat\$3)) same ((line edge) near\$3 (group\$3 cluster\$3 collat\$3 collect\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/18 10:30				S58
59	BRS 80	S58 and @ad<"20010625"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/18 09:58				S59
60	BRS 1	((smeat\$3) same ((line\$1 edge\$1) near\$3 (detect\$3 locat\$3)) same ((line edge) near\$3 (group\$3 cluster\$3 collat\$3 collect\$3)) and @ad<"20010625"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/18 08:38				S60

New

	Type	Hits	Search Text	DBs	Time Stamp	Com ments	Error Defi nition	Error s	Ref #
61	BRS	50	((line\$1 near3 (character text\$1)) near3 (detect\$3 locat\$3)) same ((line edge) near3 (group\$3 cluster\$3 coliat\$3 collect\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/18 09:57				S62
62	BRS	44	S62 and @ad<"20010625"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/18 10:39				S63
63	BRS	2	(OCR (character adj1 recognition)) same (((line\$1 edge\$1) near3 detect\$3) with ((line edge) near3 (group\$3 cluster\$3 coliat\$3 collect\$3)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/18 10:37				S64
64	BRS	29	(OCR (character adj1 recognition)) and (((line\$1 edge\$1) near3 detect\$3) with ((line edge) near3 (group\$3 cluster\$3 coliat\$3 collect\$3)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/18 11:50				S65
65	BRS	21	S65 and @ad<"20010625"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/18 11:52				S66
66	BRS	54	(OCR (character adj1 recognition)) same (line\$1 near3 (group\$3 cluster\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/18 11:51				S67
67	BRS	49	S67 and @ad<"20010625"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/18 11:52				S68
68	BRS	15	((line stroke) near3 preserv\$3) with threshold\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/18 15:27				S69
69	BRS	0	(line\$1preserving stroke\$1preserving) with threshold\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/18 15:27				S70
70	BRS	14	S69 and @ad<"20010625"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/18 15:28				S71

	Type	Hits	Search Text	DBs	Time Stamp	Com ments	Error Defi nition	Error s	Ref #
71	BRS	1	(smea\$3 blur\$4) with (morphological\$2 near3 (expa\$4 grow\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/18 16:03				S72
72	BRS	2	(smea\$3 blur\$4) same (morphological\$2 near3 (expa\$4 grow\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/18 16:04				S73
73	BRS	0	"address block location" and Hough	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 07:07				S74
74	BRS	61	"address block location"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 07:07				S75
75	BRS	3	"address block location" same edge	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 07:31				S76
76	BRS	3	"address block location" same (line near3 group\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 07:14				S77
77	BRS	24	"address block" same (line near3 group\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 07:14				S78
78	BRS	19	S78 and @ad<"20010625"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 07:21				S79
79	BRS	158	"address block" same edge	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 07:21				S80
80	BRS	103	S80 and @ad<"20010625"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 07:24				S81

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors	Ref #
81	BRS	45	S75 and @ad<"20010625"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 07:35				S82
82	BRS	865	((smear\$3 blur\$4) same ((edge line) near3 (detect\$3 fit\$4 extract\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 07:33				S83
83	BRS	396	((smear\$3 blur\$4) with ((edge line) near3 (detect\$3 fit\$4 extract\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 07:34				S84
84	BRS	30	((smear\$3) with ((edge) near3 (detect\$3 extract\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 07:35				S85
85	BRS	19	S85 and @ad<"20010625"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 08:04				S86
86	BRS	58	(line near3 group\$3) same Hough	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 08:04				S87
87	BRS	19	S86 and @ad<"20010625"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 08:04				S88
88	BRS	51	S87 and @ad<"20010625"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 08:04				S89
89	BRS	86	((smear\$3 blur\$4 RL5A (run\$1length as\$1 smooth\$3)) same (edge near3 detect\$3) same (line near3 (fit\$4 detect\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 14:44				S90
90	BRS	62	S90 and @ad<"20010625"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 14:42				S91

	Type	Hits	Search Text	DBs	Time Stamp	Com ments	Error Defi nition	Error s	Ref #
91	BRS	6	(smeart\$3 RLSA (run\$1length adj1 smooth\$3)) same (edge near3 detect\$3) same (line near3 (fit\$4 detect\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 14:45				S92
92	BRS	152	(382/101,102,173- 176,195,198,202,224,225,264,270,281,289,358/462.ccls.) and @ad<"20010326" and @pd > "20040601"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 16:58				S95
93	BRS	164	(382/101,102,173- 176,195,198,202,224,225,237,257,264,270,281,289,290,358/462.ccls.) and @ad<"20010326" and @pd > "20040601"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/02/22 17:02				S96

09/887, 495



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1 Vision and the graphical simulation of spatial structure

W. A. van de Grind
January 1987 **Proceedings of the 1986 workshop on Interactive 3D graphics**

Full text available: pdf(3.51 MB) Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

One important message of this paper is that vision research is highly relevant to 3D graphics technology and that modern electronic graphical systems can and soon will strongly stimulate the further development of vision science. First an outline is given of ecological optics, the discipline trying to describe the visual information available to an active (mobile, structure-seeking) observer. Whereas ecological optics describes the available visual structure, the observables, psychophysics ...

2 Health care information systems: a personal historic review

M. F. Collen
December 1987 **Proceedings of ACM conference on History of medical informatics**

Full text available: pdf(1.14 MB) Additional Information: [full citation](#), [references](#), [index terms](#)

3 Picture Processing by Computer

Azriel Rosenfeld
September 1969 **ACM Computing Surveys (CSUR)**, Volume 1 Issue 3

Full text available: pdf(2.69 MB) Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)

4 Knowledge based approach for the verification of CAD database generated by an automated

schematic capture system

J. Y. Tou, W. H. Ki, K. C. Fan, C. L. Huang

October 1987 **Proceedings of the 24th ACM/IEEE conference on Design automation**

Full text available:  pdf(765.41 KB)


Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

CAD database generated by an automatic schematic capture system needs to be verified before it can be used in design automation. This verification is best performed by a knowledge-based expert system. Presented in this paper is the design of a knowledge-based system for the verification of CAD database generated by AUTORED. Database-driven, pattern-directed inference technique is employed to identify and correct erroneous data records due to misrecognition. This knowledge-based verification ...

5 The Quadtree and Related Hierarchical Data Structures

Hanan Samet

June 1984 **ACM Computing Surveys (CSUR)**, Volume 16 Issue 2


Full text available:  pdf(4.87 MB)

Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)

6 Document image understanding

Sargur N. Srihari

November 1999 **Proceedings of 1986 ACM Fall joint computer conference**

Full text available:  pdf(1.38 MB)

Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)

7 Improving edge detection by an objective edge evaluation

Qiuming Zhu

April 1992 **Proceedings of the 1992 ACM/SIGAPP Symposium on Applied computing: technological challenges of the 1990's**

Full text available:  pdf(919.92 KB)

Additional Information: [full citation](#), [references](#), [index terms](#)

8 A computer vision system for automated corn seed purity analysis

Jack C. H. Chung, M. Litt, G. Leininger

June 1990 **Proceedings of the third international conference on Industrial and engineering applications of artificial intelligence and expert systems - Volume 1**


Full text available:  pdf(798.92 KB)

Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

Electrophoresis gel analysis is a viable technique for determining the purity of hybrid corn seeds. Visually analyzing the electrophoretic gel images is a very tedious and time-consuming task. In this paper, a computer vision system integrating image processing and pattern recognition techniques with domain-specific structural information to automate the electrophoresis gel scoring procedure is presented. A set of image processing algorithms are developed to perform extraction of the region ...

9 Two complementary techniques for digitized document analysis


George Nagy, Junichi Kanai, Mukkai Krishnamoorthy, Mathews Thomas, Mahesh Viswanathan
January 2000 **Proceedings of the ACM conference on Document processing systems**

Full text available:  [pdf\(576.67 KB\)](#)

Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)

10 Computational Approaches to Image Understanding


Michael Brady
January 1982 **ACM Computing Surveys (CSUR)**, Volume 14 Issue 1

Full text available:  [pdf\(10.04 MB\)](#)

Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)

11 Picture Segmentation by a Tree Traversal Algorithm

Steven L. Horowitz, Theodosios Pavlidis
April 1976 **Journal of the ACM (JACM)**, Volume 23 Issue 2


Full text available:  [pdf\(1.08 MB\)](#)

Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

In the past, picture segmentation has been performed by merging small primitive regions or by recursively splitting the whole picture. This paper combines the two approaches with significant increase in processing speed while maintaining small memory requirements. The data structure is described in detail and examples of implementations are given.

12 An SPMD/SIMD parallel tokenizer for APL

Robert Bernecky
June 2003 **Proceedings of the 2003 conference on APL: stretching the mind**

Full text available:  [pdf\(111.27 KB\)](#)

Additional Information: [full citation](#), [abstract](#), [references](#)

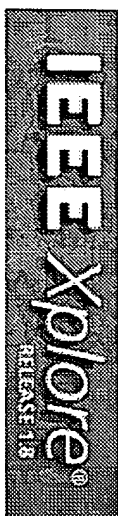
We describe a highly parallel (SIMD within SPMD) tokenizer for the APL language, itself written in APL. The tokenizer does not break any new ground in the world of parallel computation, but does serve the didactic purpose of demonstrating that a large amount of parallelism exists in non-numeric computation. We plan to release the APEX APL Compiler, including the tokenizer, under the GNU Public License.

09/887, 475

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1 Postal address block location in real time

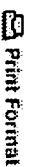
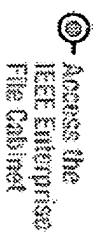
Palumbo, P.W.; Srihari, S.N.; Soh, J.; Sridhar, R.; Demjanenko, V.;
 Computer, Volume: 25, Issue: 7, July 1992
 Pages: 34 - 42

[Abstract] [PDF Full-Text (772 KB)] IEEE JNL

2 Address block location using character recognition and address syntax

Li, J.; Palumbo, P.W.; Srihari, S.N.;
 Document Analysis and Recognition, 1993., Proceedings of the Second
 International Conference on, 20-22 Oct. 1993
 Pages: 330 - 334

[Abstract] [PDF Full-Text (544 KB)] IEEE CNF



3 Address block location on complex mail pieces

Yu, B.; Jain, A.K.; Mohiuddin, M.; Document Analysis and Recognition, 1997., Proceedings of the Fourth International Conference on , Volume: 2 , 18-20 Aug. 1997
Pages:897 - 901 vol.2

[Abstract] [PDF Full-Text (1004 KB)] IEEE CNF

4 Recognition of handwritten Chinese postal address using neural networks

Yih-Ming Su; Jhing-Fa Wang; Circuits and Systems, 1998. ISCAS '98. Proceedings of the 1998 IEEE International Symposium on , Volume: 3 , 31 May-3 June 1998
Pages:25 - 28 vol.3

[Abstract] [PDF Full-Text (624 KB)] IEEE CNF

5 Locating destination address block on handwritten Korean envelopes

Seong-Whan Lee; Ki-Cheol Kim; Pattern Recognition, 1994. Vol. 2 - Conference B: Computer Vision & Image Processing., Proceedings of the 12th IAPR International. Conference on , Volume: 2 , 9-13 Oct. 1994
Pages:619 - 621 vol.2

[Abstract] [PDF Full-Text (252 KB)] IEEE CNF

6 On texture in document images

Jain, A.K.; Bhattacharjee, S.K.; Chen, Y.; Computer Vision and Pattern Recognition, 1992. Proceedings CVPR '92., 1992 IEEE Computer Society Conference on , 15-18 June 1992
Pages:677 - 680

[Abstract] [PDF Full-Text (512 KB)] IEEE CNF

7 Applying intelligent robotics and vision to mail processing

Lee, J.; Glickman, F.; Intelligent Control, 1988. Proceedings., IEEE International Symposium on , 24-26 Aug. 1988

Pages: 724 - 729

[\[Abstract\]](#) [\[PDF Full-Text \(396 KB\)\]](#) **IEEE CNF**

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